

Transaction Information

Tool ID	J25X
Tool Status	Connected
Location	Burlington, USA
Wafer Size	200 mm
Fab Section	Metrology
Tool Available Date	2024-01-23

General Product Information

Vendor Supplier	AMAT
Model	Complus MP
Vintage	2003
Serial No	T236
Asset Description	Defect Inspection and Review for Semiconductors
Software Version	V9.6
CIM	SECS, GEM
Process	Defect Inspection

Hardware Configuration

System Type	Description	Quantity	Status
Main System	Defect Inspection		OK
Factory Interface	Open Cassette	1	OK
Handler System	Dual		OK
Options System			
Others			

Excluded Items List (Pumps, Chillers & Abatement are all excluded)

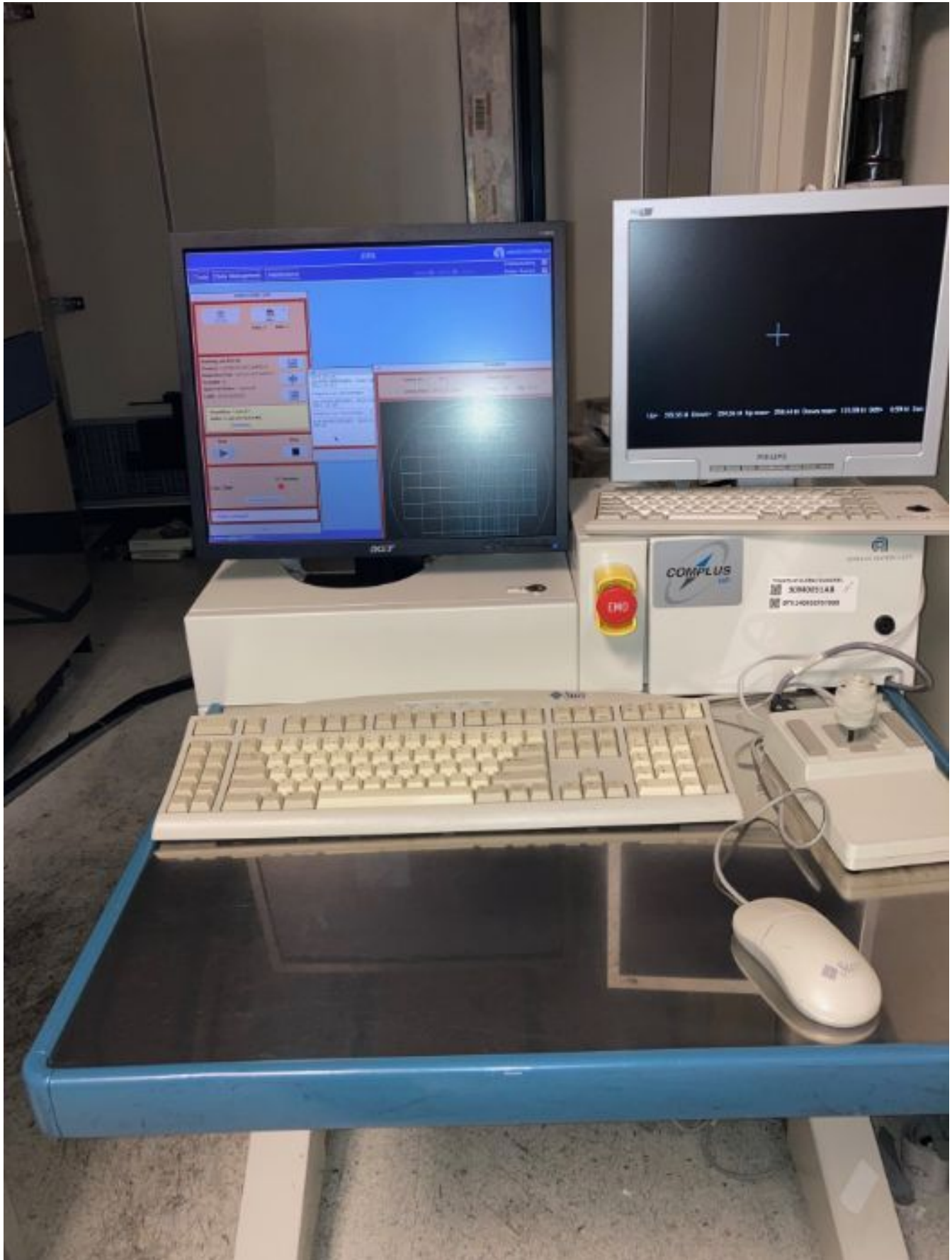
Description	Quantity
NONE	

* List above may or may not be comprehensive. Tool is sold in "as-is" condition. To ensure your satisfaction, we strongly recommend to make an appointment to inspect this and every tool you are interested in.

Tool Pictures

General

EFM, Front and WorkStation










Manufacture Serial

Serial Number Plate

	APPLIED MATERIALS®	9 OPPENHEIMER ST. REHOVOT 76705 POB 4030 ISRAEL
ComPLUS MP		
SERIAL No. <u>T236</u>		
YEAR OF CONSTRUCTION: <u>2003</u>		
OVER CURRENT PROTECTION PROVIDED AT MACHINE SUPPLY TERMINALS.		
SUPPLY VOLTAGE: 208V AC 3 PH 5 WIRE 50/60 HZ		
LARGEST LOAD AMPERE RATING: 17A		
MAXIMUM SYSTEM RATING: 7.2 KVA		
FULL LOAD CURRENT: 28A		
INTERRUPT CURRENT: 10 KA		
SCHEMATIC DRAWINGS NUMBER: 753-27100-EL		
WEIGHT: 2800 KG		
		
Product conforms to 21 CFR 1040.10, 1040.11 At the Date of Manufacture.		
		
P/N 4400220		